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				ATTY DOCKET NO. 262666US0PCT		New U.S. PCT Application Based on PCT/JP02/05920				
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LIST OF	REFEF	RENCES CITED BY API	PLICANT	Yoko HANADA, et al.						
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/J.P./	AK	2002-179535	06/26/02	JP (with English abstract)		7 5	<u>`</u>	NO NO		
/J.F./	AL	9-194335	07/29/97	JP (with English abstract)				NO		
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	AN	2000-143458	05/23/00	JP (with English abstract)				NO		
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	AT	0 078 597	05/11/83	EP EP				NO		
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/J.P./	AW	Koushouhin Kagaku, pages 130-131								
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Examiner	/Jeffrey Palenik/					Date Considered 10/30/2007				
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				June 9, 2005			1615				
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	AZ					Additional References sheet(s) attached					
Examiner	/Jeffrey Palenik/					Date Considered 10/30/2007					
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